

<b>Notice of References Cited</b>	Application/Control No. 10/706,006		Applicant(s)/Patent Under Reexamination NOMURA ET AL.	
	Examiner John P. Sheehan		Art Unit 1742	Page 1 of 1

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*	B	US-2003/0019546 A1	01-2003	Kanekiyo et al.	148/105
*	C	US-2002/0112785 A1	08-2002	Sekine et al.	148/302
*	D	US-5,352,302 A	10-1994	Takagi et al.	148/101
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	M	US-			

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**NON-PATENT DOCUMENTS**

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